## Flexible ultraviolet photodetector based on single crystalline MoO<sub>3</sub> nanosheet

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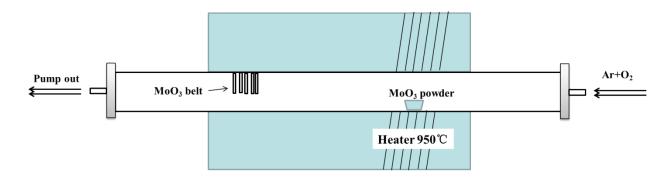
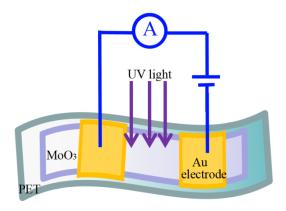
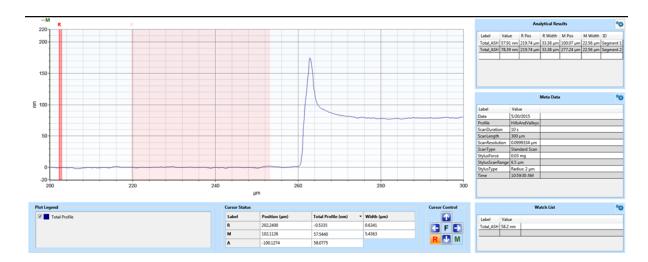


Fig. S1 Schematic diagram of the horizontal physical vapor deposition system



**Fig. S2** Schematic diagram of the flexible metal-semiconductor-metal structure UVPD based on MoO<sub>3</sub>/PET



**Fig. S3** Thickness of the MoO<sub>3</sub> nanosheet using for the MSM UVPD measured by Bruker Dektak XT profilometer, which is found to be 78.4 nm.